

THURSDAY PM

XRD

MILE HIGH RESOLUTION XRD

EVERGREEN D

Chair: K. Evans-Lutterodt, Brookhaven National Laboratory, Upton, NY

- 3:50 D-73 High Resolution X-ray Diffraction of III-Nitride Wide Bandgap Semiconductors**
Q. Sun, B. Leung, J. Han, Yale University, New Haven, CT
- 4:10 D-17 High-Resolution Reciprocal Space Mapping of InGaAs/GaAs Structures: From Pseudomorphic to Fully Relaxed State**
A. Ulyanenko, Bruker AXS GmbH, Karlsruhe, Germany
F. Rinaldi, S. Menzel, Ulm University, Ulm, Germany
A. Benediktovich, A. Zhilik, I. Feranchuk, Belarussian State University, Minsk, Belarus
K. Saito, Bruker AXS K.K., Yokohama, Japan
- 4:30 D-36 In-Plane Diffraction Analysis for Twist/Twin Structure of Non-Polar A-Plane GaN**
Y.-i. Jang, K.-h. Park, K.-h. Bang, LG Advanced Research Institute, Seoul, Korea
- 4:50 D-1 Effect of Substrate Temperature on the Structural, Optical and Electrical Properties of Silver Indium Selenide Films Prepared by Laser Ablation**
D. Pathak, R.K. Bedi, Guru Nanak Dev University, Amritsar, India
D. Kaur, Indian Institute of Technology, Roorkee, India

THURSDAY PM

XRF

X-RAY IMAGING

EVERGREEN B

Chair: G.J. Havrilla, Los Alamos National Laboratory, Los Alamos, NM

- 2:00 F-22 Invited—X-ray Absorption Imaging for Analysis of Gas Discharges in Energy-Efficient Lighting**
J.J. Curry, NIST, Gaithersburg, MD
- 2:30 F-3 STXM Imaging of Organic Coatings on Grains in Primitive Interplanetary Dust: Implications for Formation of Pre-Biotic Organic Matter and Grain Sticking in the Early Solar System**
G.J. Flynn, SUNY-Plattsburgh, Plattsburgh, NY
S. Wirick, C. Jacobsen, SUNY- Stony Brook, Stony Brook, NY
L.P. Keller, NASA Johnson Space Center, Houston, TX
S.A. Sandford, NASA Ames Research Center, Moffett Field, CA
- 2:50 F-37 Macroscopic X-ray Fluorescence Capability for Large-Scale Elemental Mapping**
H.M. Volz, G.J. Havrilla, R.M. Aikin, Jr., V.M. Montoya, A.N. Duffield, Los Alamos National Laboratory, Los Alamos, NM
- 3:10 F-29 Overlay of Laboratory-Based 3D X-ray Imaging Systems**
B.M. Patterson, G.J. Havrilla, B. Jackson, Los Alamos National Laboratory, Los Alamos, NM
- 3:30 Break**
- 4:00 F-26 Invited—X-ray Chemical Imaging in Scanning and Projection Modes in the Laboratory**
K. Tsuji, K. Nakano, Osaka City University, Osaka, Japan